



A Machine Learning Framework for NAND Flash Lifetime Extension

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A World of Machines... Learning

In the last few years, machine learning has become ubiquitous



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The common approach today is:
Do you have a problem? Fix it with Machine Learning!



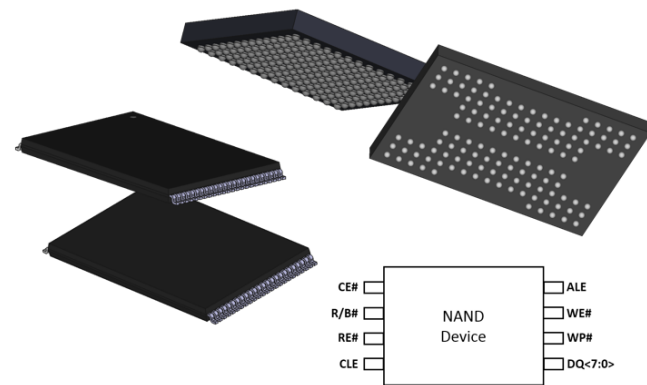
The “Devil” in Machine Learning

Using machine learning is not as simple as it appears...

- One of the biggest problems when using machine learning is neither the algorithm nor the implementation...
- “The problem is not the problem. The problem is how you define the problem...”

NAND Flash Memories Today

- 3D up to 96 layers
- 8 Tbits in a single BGA package
- Quad level cell (QLC)
- Circuits under array
- I/O bus @ 1200 MT/s
- $t_{\text{PROG}} \approx 3 \text{ ms}$
- $t_{\text{READ}} \approx 100 \mu\text{s}$
- $t_{\text{ERASE}} \approx 10 \text{ ms}$
- Cost per Gb \approx HDD

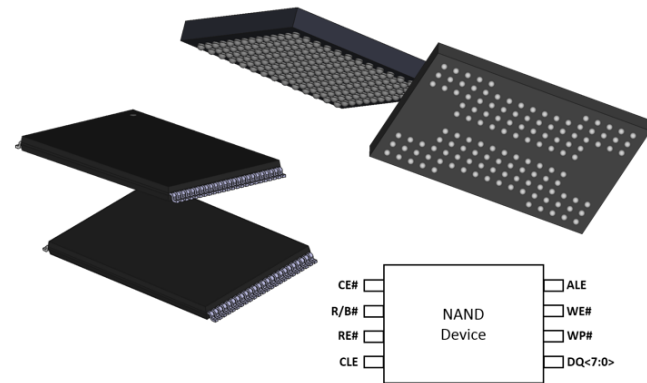


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Reliability!!
NAND FER fighting against the Shannon limit



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NAND Flash

- The higher the data reliability, the longer the device's lifetime (and the cheaper the solution...)
- Problem statement: increase data reliability to extend NAND flash's lifetime

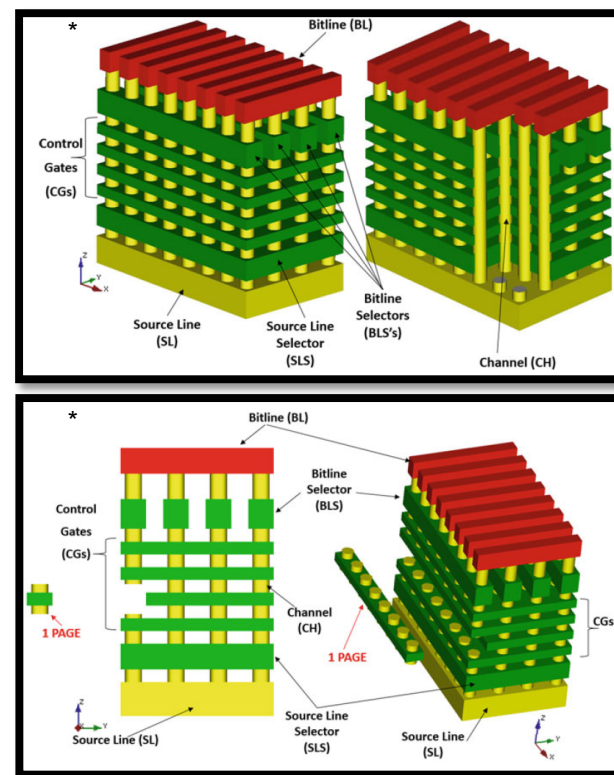
...Now what?...



3D NAND Flash Memories

Having a deep understanding of the device's physics is the only way to get good data reliability

- 3D NAND flash is a stack of multiple memories
- Array architecture
- Cell-to-cell variability





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“...Welcome to the jungle...”

Many parameters impact NAND flash reliability including soft info, code-rate, cycling speed, and temperature.

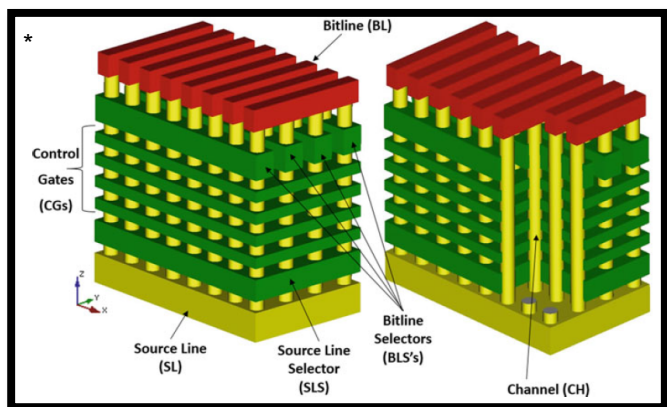
- Too many parameters to look at
- Too many possible correlations
- Too many features

There is no guarantee that we'll find the best setting for each working conditions...



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Problem? Use Machine Learning



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R. Micheloni (ed.), *3D Flash Memories*, DOI 10.1007/978-94-017-7512-0_3

NAND flash know-how

Machine learning know-how

...Now what?...

Flash Memory Summit 2018
Santa Clara, CA

* Rino Micheloni, *3D Nand Flash Memories*, Springer 2016



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Goals

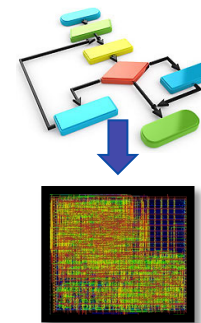
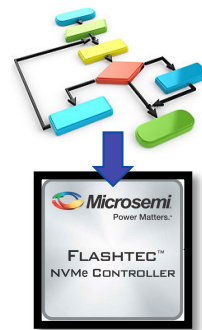
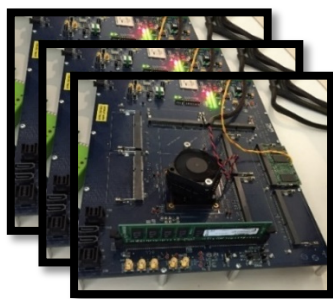
What do we want to achieve?

- A framework able to test which parameters impact the reliability of a NAND flash (and which parameters do not)
- An framework able to tune these parameters depending on the reliability target
- Output: An algorithm (model) able to learn how to enhance the reliability in a completely agnostic and autonomous way → Machine Learning!
- Remember, we are looking for a framework and not an algorithm! The algorithm is just the output of the framework.



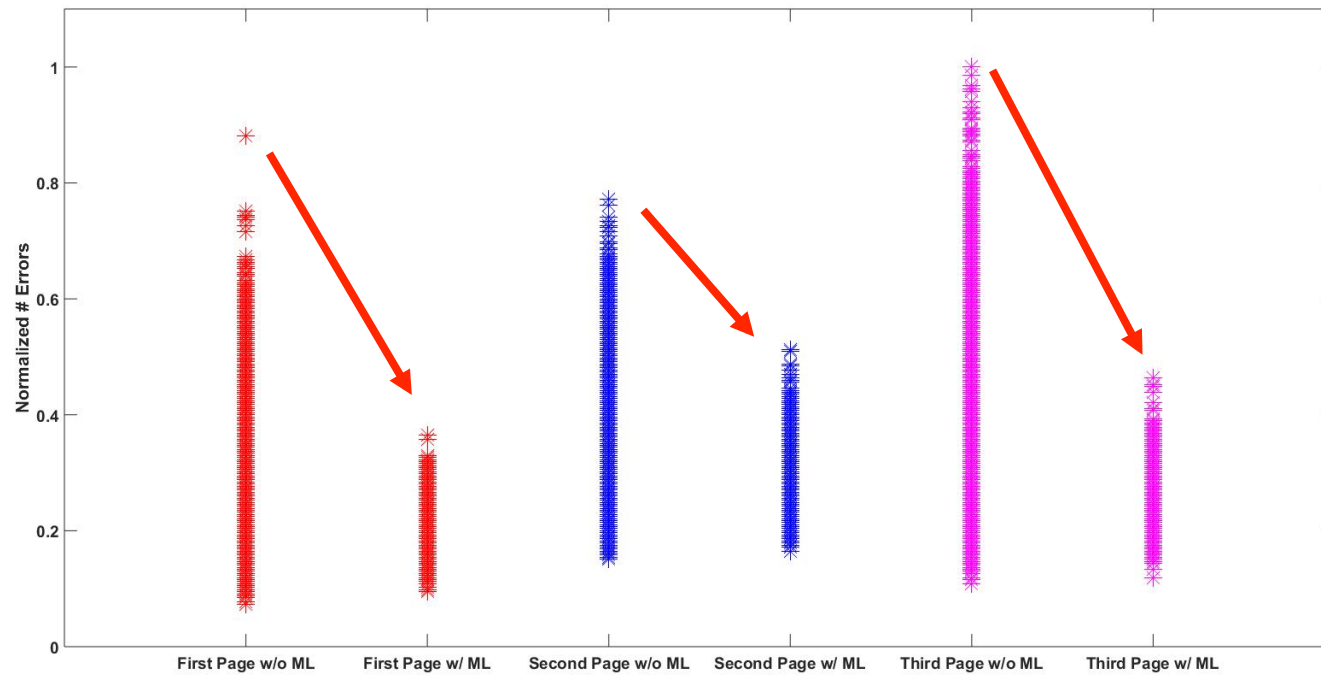
Machine Learning Framework at FSPL

- Characterization of NAND flash memories
- Brute force testing of thousands of different machine learning algorithms
- Create a software model of the target algorithms
- Implement best candidate algorithm at firmware level
- Hardware acceleration



- Test with NVMe Flashtec™ controller

Example

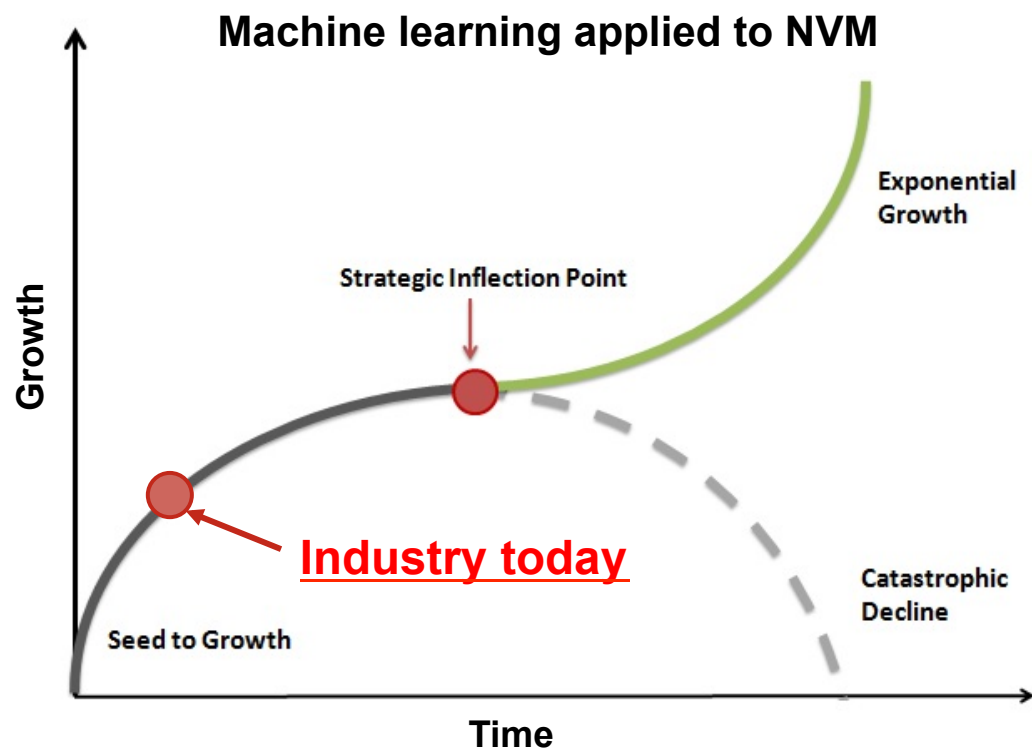


Firmware to hardware latency gain $\approx 100x$



Where Are We Today?

“...a strategic inflection point is a time in the life of business when its fundamentals are about to change. That change can mean an opportunity to rise to new heights. – Andy Grove”

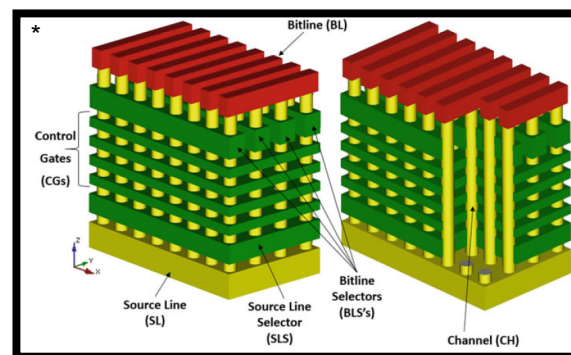




Conclusions: M²ZC Conjecture

“In hyperscaled NAND flash memories each layer will be optimized by machine learning”

- **Takeaway #1:** Does machine learning work with NAND flash memories? → Yes!
- **Takeaway #2:** Are humans obsolete? → Don't think so! We still need to guide the machine (a student can learn at a much faster rate with a good teacher...)



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Thanks

Q&A

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